

**INFORMATION DISCLOSURE CITATION**

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Serial No.: 10/804,194

Applicants: Hirotoshi TERADA et al.

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Filing Date: March 19, 2004

Group Art Unit: Unassigned

2873

**U.S. PATENT DOCUMENTS**

*Examiner Initial	Document Number	Date	Name	Class	Sub Class	Filing Date

**FOREIGN PATENT DOCUMENTS**

	Document Number	Date	Country	Class	Sub Class	Translation	
						YES	NO
/JRG/	WO 98/58288	Dec. 23, 1998	PCT				
↓	JP 2002-512697	Apr. 23, 2002	Japan			Abstract	
	JP 2000-235038	Aug. 29, 2000	Japan			Abstract	
	JP 2003-130781	May 8, 2003	Japan			Abstract	
	JP 2003-141768	May 16, 2003	Japan			Abstract	
	JP 2002-236087	Aug. 23, 2002	Japan			Abstract	
	JP 2000-121930	April 28, 2000	Japan			Abstract	
	JP 8-315404	Nov. 29, 1996	Japan			Abstract	
	JP 2000-11423	Jan. 14, 2000	Japan			Abstract	
	JP11-203711	July 30, 1999	Japan			Abstract	
	JP 11-202194	July 30, 1999	Japan			Abstract	

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)**


Examiner

/James R Greece/

Date Considered

08/30/2007

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## U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Sub Class	Filing Date
↓ /JRG/	5,939,709	August 17, 1999	Ghislain et al.	250	216	June 19, 1997
	5,422,498	June 6, 1995	Nikawa et al.	257	48	April 13, 1994
	5,208,648	May 4, 1993	Batchelder et al.	356	237	March 11, 1991
	5,220,403	June 15, 1993	Batchelder et al.	356	345	September 30, 1992
	5,004,307	April 2, 1991	Kino et al.	350	1.2	April 12, 1990
	5,125,750	June 30, 1992	Corle et al.	359	819	March 14, 1991
	6,594,086 B1	July 15, 2003	Pakdaman et al.	359	656	January 16, 2002
	6,475,398 B2	November 5, 2002	Kitahata	216	2	September 25, 2001
	6,608,359 B2	August 19, 2003	Kitahata	257	432	August 29, 2002
	6,656,029 B2	December 2, 2003	Kitahata	451	384	August 29, 2002
	6,621,275 B2	September 16, 2003	Cotton et al.	324	537	November 28, 2001
	6,002,792	December 14, 1999	Oguri et al.	382	145	February 29, 1996
	6,687,058 B1	February 3, 2004	Ippolito et al.	359	656	June 20, 2000
	6,441,359 B1	August 27, 2002	Cozier et al.	250	216	October 7, 1999
	2003/0202255 A1	October 30, 2003	Pakdaman et al.	359	656	May 19, 2003
	2003/0210057 A1	November 13, 2003	Cotton et al.	324	501	June 9, 2003

## FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Sub Class	Translation Yes	No
↓ /JRG/	JP 2002-189000 (corresponds to USP Nos. 6,475,398, 6,608,359 & 6,656,029)	July 5, 2002	Japan	—	—	Abstract
	JP 05-157701	June 25, 1993	Japan	—	—	Abstract
	JP 06-300824 (corresponds to USP 5,422,498)	October 28, 1994	Japan	—	—	Abstract
	JP 07-190946 (corresponds to USP 6,002,792)	July 28, 1995	Japan	—	—	Abstract
	JP 7-18806 (corresponds to USP Nos. 5,208,648 & 5,220,403)	March 6, 1995	Japan	—	—	Abstract
	JP 11-003534	January 6, 1999	Japan	—	—	Abstract
	JP 2001-023230	January 26, 2001	Japan	—	—	Abstract
	EP 0 977 192 A1	February 2, 2000	Europe	—	—	

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

↓ /JRG/	ISTFA, November 2003, "Conference Proceedings from the 29th International Symposium for Testing and Failure Analysis", pp. 325-329.
	ISTFA 2003, "Photoemission and OBIRCH Analysis with Solid Immersion Lens (SIL)", pp. 1-20.

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